

**Search Notes**

Application/Control No.

10/782,481

Examiner

James D. Stein

Applicant(s)/Patent under  
Reexamination

TELKAMP ET AL.

Art Unit

2874

**SEARCHED**

Class	Subclass	Date	Examiner
385	16,17,39	1/5/2006	JDS
385	42,50,131	1/5/2006	JDS

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner
USPGPUB interference search -- see attached EAST search hist		1/5/2006	JDS

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
See attached EAST search history -- UPDATED	1/5/2006	JDS
385/14-52,129 -- UPDATED Keyword search	1/5/2006	JDS
IEEE and INSPEC: matrix, switch, waveguide, plane, layer, parallel, perpendicular -- UPDATED	1/5/2006	JDS
USPGPUB interference search -- see attached EAST search history	1/5/2006	JDS